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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10083481	02/27/2002	250		2881	

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****CONTINUING DATA VERIFIED:**
THIS APPLICATION IS A CON OF 09/883,184 06/19/2001
WHICH IS A CON OF 09/131,383 08/07/1998 PAT 6,348,690

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**** FOREIGN APPL.ICATIONS VERIFIED:**
JAPAN 9-212908 03/07/1997

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO	
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		29273/559	
Verified and Acknowledged Examiners's initials			
TITLE : Method and an apparatus of an inspection system using an electron beam			
U.S. DEPT. OF COMM./PAT. & TM-PTO-435L (Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg. Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		Application Examiner	
		PREPARED FOR ISSUE	
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